

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	769	257/417.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/17 08:58
S2	6	("4411741" "5911873" "4385274").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 09:51
S3	2	"EP 947829"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 16:18
S4	2	"DE 4239319"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 16:21
S5	5	"DE 3144459"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 14:29
S6	1	"DE 19849932"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 14:30
S7	16362	sensor and (air adj gap)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 09:12
S8	53	S7 and (guard adj ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 10:48

S22	334627	substrate near surface	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 09:22
S23	36450	S22 and insulator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 09:22
S24	8688	S23 and (rings or ridges or elevations)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 09:42
S25	86	S24 and (surface near conductivity)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 09:22
S26	186	S23 and "insulator ring"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 10:00
S27	1897	73/23.2,31.06.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:35
S30	18	air adj gap and 73/23.2,31.06.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 10:01
S31	3	("3584499" "4860574" "6430987").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/11 10:19
S33	33	air adj gap and 257/417.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/11 10:19

S34	261	chemfet	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:46
S35	9	("4838088" "4930043" "4999735" "5006487" "5008774" "5025346" "5043043" "5121180" "5216490").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/11 10:52
S36	6950	257/417,108,415,418,327,252,253, 127,339,225,73,222,225,488, 489;73/23.2,31.06.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:55
S37	25	S36 and (air adj gap) and ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:19
S38	833	S36 and ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:19
S40	3061	S36 and (insulat\$3 ring) and @ad<"20030101"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:20
S41	10	S36 and (insulat\$3 adj ring) and @ad<"20030101"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:23
S42	1622	insulator adj ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:26
S43	100	insulator adj ring same substrate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:29

S44	27296	insulat\$3 adj layer and ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:30
S45	5607	insulat\$3 adj layer and ring and sensor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:30
S46	6731	insulat\$3 adj layer same ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:31
S47	443	insulat\$3 adj layer same ring same guard	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 11:31
S48	70	insulat\$3 adj layer same ring same guard same channel	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 12:53
S49	329	"insulative rings"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 12:55
S50	40	SGFET	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 12:55
S51	28	("4671852").URPN.	USPAT	OR	ON	2005/08/11 13:06
S52	5	CCFET	USPAT	OR	ON	2005/08/11 13:10
S53	8	("6175394").URPN.	USPAT	OR	ON	2005/08/11 13:07
S54	4	("5126812" "5313836" "5417111" "5504356").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/11 13:08
S55	3654	guard adj ring	USPAT	OR	ON	2005/08/11 13:10
S56	88	(guard adj ring) and (air adj gap)	USPAT	OR	ON	2005/08/11 13:11

S57	9616	257/417,108,415,418,327,252,253, 127,339,225,73,222,225,488, 489;73/23.2,31.06;73/23.2,31. 06;204/424,431, 432;340/634;324/464,465.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 13:32
S58	188	S57 and (guard adj ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 15:17
S59	2	"20050146007"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 15:11
S60	246	S57 and (insulat\$3 with ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 15:35
S61	332	S57 and (field adj plates)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 15:35
S62	2	("4764797").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 16:31
S63	4	"EP 155726"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 16:18
S64	2	"DE 4333875"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 16:25

S65	2	"20020157950"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 16:38
S66	1576	Frerichs, Heinz-Peter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/11 16:38
S68	22	"Frerichs, Heinz-Peter".in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:22
S71	286	"increase surface resistance"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 08:39
S72	36039	pattern and substrate and (increase same resistance) and surface	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 08:40
S73	2694	S72 and (ring same structure)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 08:40
S74	9616	257/417,108,415,418,327,252,253, 127,339,225,73,222,225,488, 489;73/23.2,31.06;73/23.2,31. 06;204/424,431, 432;340/634;324/464,465.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:45
S75	35	S73 and S74	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 08:40

S76	2	"4764797".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:24
S77	4637734	ep "155726"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:24
S78	4	"ep 155726"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:32
S79	25	"surface conductivity" and S74	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:39
S80	276	"surface conductivity" and (elevation or island)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:42
S81	0	"surface conductivity" and (elevation or island) near (channel and ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:43
S82	3	(elevation or island) near (channel and ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:43
S83	315323	(channel and ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:43

S84	2714	(channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:43
S85	0	insulat\$3 near between near (channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:44
S86	1	insulat\$3 near (channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:44
S87	1	insulat\$4 near (channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:44
S88	239	island and (channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:44
S89	0	island near (channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:44
S90	32	island same (channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:51
S91	73	insulator same (channel and "guard ring")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:53

S92	5605	STI and barrier	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:53
S93	330	S92 and sensor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 09:54
S95	5802	chemical adj sensor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:18
S96	11	S95 and (guard adj ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:19
S97	21973	gas adj sensor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:20
S98	13	S97 and (guard adj ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:23
S99	9273	(guard adj ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:23
S10 0	2512	(guard adj ring) and (air gap)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:24

S10 1	171	(guard adj ring) and (air adj gap)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:29
S10 3	261	257/253.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:40
S10 4	4	("4054875" "5837562" "6049313" "6282352").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/12 14:32
S10 5	2	("6555856").URPN.	USPAT	OR	ON	2005/08/12 14:32
S10 6	173	257/252.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:40
S10 7	261	chemfet	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:46
S10 8	0	S107 and (guard adj ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:53
S10 9	94	S107 and ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:47
S11 0	6950	257/417,108,415,418,327,252,253, 127,339,225,73,222,225,488, 489;73/23.2,31.06.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 14:15

S11 1	6950	S110	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:53
S11 2	179	S110 and (guard adj ring)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 15:01
S11 3	41	S112 and (gap or cavity)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 14:53
S11 4	2640	S110 and sensor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 15:01
S11 6	58	S114 and guard	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/12 15:02
S11 7	2	"20020157950"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 09:51
S11 8	99	("6013936" "5883424" "5382825" "5884943" "5769117" "6206976" "4349394" "4480429" "4521795" "4812756" "4837443" "4874714" "4881107" "4963819" "5223919" "5232009" "5311900" "5423126" "5430311" "5472284" "5538492" "5563757" "5775169" "5859450" "6028010" "6082003" "6111271" "6509203" "5427111" "4862016" "3798512" "4633289" "5043781" "5274263" "6225241" "6225241" "6399991" "6707128" "4504801" "5651048" "5030853" "5305269" "5384730" "5396457" "5489814" "6111475" "5698884" "5786620" "5885876" "5814869").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 09:58

S119	52	resistive adj field adj plate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 10:22
S120	88	"conductive field plates"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 10:34
S121	129	"equipotential rings"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 10:34
S122	27075	(chemical or gas) adj sensor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 10:49
S123	29	S122 and (suspended or floating) adj gate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 10:49
S124	14	("4306196" "4322687" "4462002" "4495470" "4725348" "4810973" "4987379" "4992755" "5233543" "5726597" "5793230" "5880614" "6002355" "6445171").PN	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 10:57
S125	2742	field with isolation with structure	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 10:59
S126	168	field adj isolation adj structure	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 10:58
S127	168	field adj isolation adj structure	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:01
S129	12270	shallow adj trench adj isolation	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:01
S130	716	S129 and sensor	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:10

S13 1	666	S130 and (gas or ion or chemical)	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:03
S13 2	400	S131 and @ad<"20030101"	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:04
S13 3	2	S129 and ((gas or ion or chemical) adj sensor)	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:11
S13 4	12173	((gas or ion or chemical) adj sensor)	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:11
S13 5	59202	((gas or ion or chemical) with sensor)	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:12
S13 6	13785	S135 and ring	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:12
S13 7	36101	ring adj structure	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:13
S13 8	405	S137 and S135	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:13
S13 9	302	S138 and @ad<"20030101"	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:22
S14 0	217	S139 and substrate	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/15 16:22
S14 1	1424	73/23.2.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:33
S14 3	501	73/31.06.ccls. and @ad<"20030101"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:35
S14 4	1094	257/417.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:46

S14 5	675	257/417.ccls. and @ad<"20030101"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:46
S14 6	1	"4161744".pn.	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/16 13:49
S14 8	4469	semiconductor and surface and geometry and resistive and @ad<"20030101"	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/16 13:51
S14 9	109	semiconductor and (surface adj geometry) and resistive and @ad<"20030101"	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/16 14:04
S15 0	525	73/31.06.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 13:54
S15 1	813	semiconductor and (surface adj geometry) and @ad<"20030101"	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/16 14:04
S15 2	813	semiconductor and (surface adj geometry) and @ad<"20030101"	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/16 14:04
S15 3	187	semiconductor and sensor and (surface adj geometry) and @ad<"20030101"	US-PGPUB; USPAT; USOCR	OR	ON	2005/08/16 14:04
S15 4	262	257/488.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 14:15
S15 5	86	257/489.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:43
S15 6	825	257/415.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:55

S15 7	6956	257/417,108,415,418,327,252,253, 127,339,225,73,222,225,488, 489;73/23.2,31.06.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:56
S15 8	596	257/327.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:55
S15 9	154	257/127.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:56